

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10538126	KUROIWA ET AL.
	Examiner	Art Unit
	Jaisle, Cecilia M	1624

SEARCHED			
Class	Subclass	Date	Examiner
514	248	9/21/2007	Cecilia Jaisle
540	461, 578	9/21/2007	Cecilia Jaisle
544	235, 236	9/21/2007	Cecilia Jaisle
514	248	5/7/2008	C. Jaisle
544	235, 236	8/21/2008	C. Jaisle

SEARCH NOTES			
Search Notes	Date	Examiner	
STN and Inventor Names searched by STIC	9/21/2007	Cecilia Jaisle	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
544	235, 236	8/21/2008	C. Jaisle